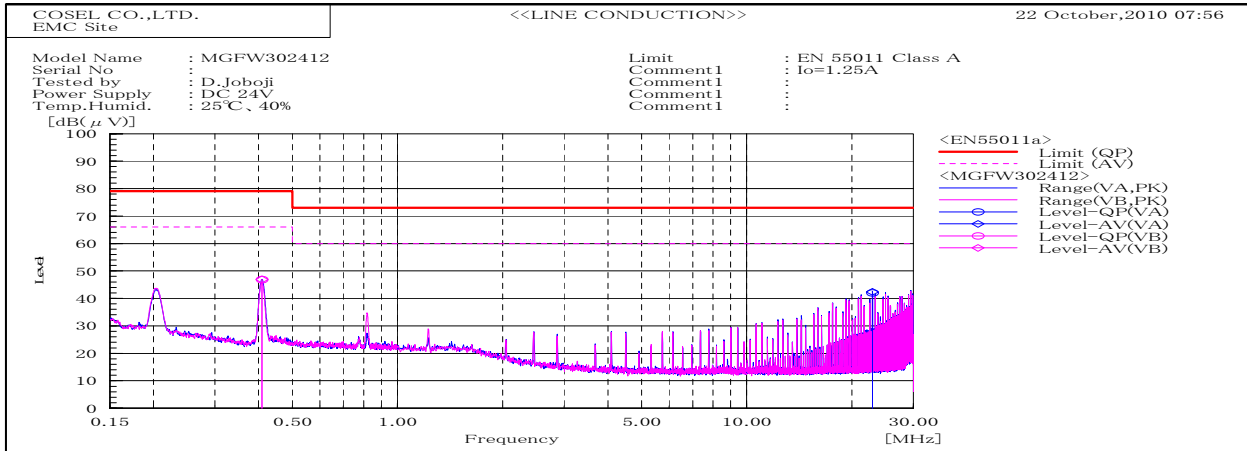
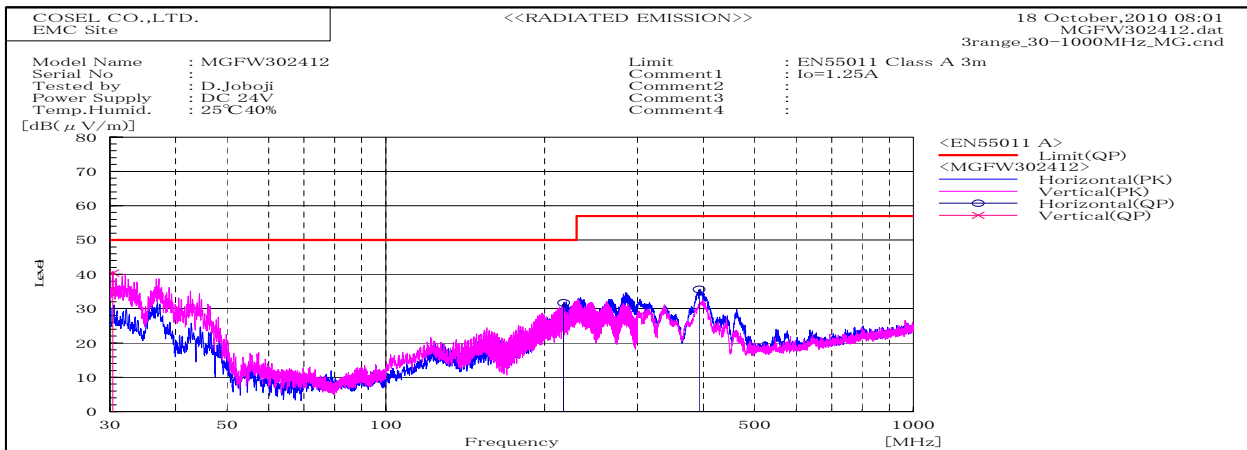


DATA SHEET		Date	22-Oct-10
Model	MGFW302412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	D.Joboji



Frequency MHz	Harm	Line Phase	Reading dB(μV)		Factor dB	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.40939		VB	36.8	36.9	10	46.8	46.9	79	66	32.2	19.1	Pass	
22.91515		VA	31.2	31.6	10.8	42	42.4	73	60	31	17.6	Pass	



Frequency MHz	Polarization	Stability	Reading dB(μV)		Space Loss dB	Level dB(mW)	Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	QP	QP				
30.406	V	Stable	54	-13.6		40.4	50	9.6	Pass	101	313	
217.428	H	Stable	52.7	-21		31.7	50	18.3	Pass	158	185	
392.575	H	Stable	50.5	-14.9		35.6	57	21.4	Pass	101	182	

# DATA SHEET

Model	Circuit used for measurement
Test	EMI Line conduction & Radiated emission

## 1. Line conduction



## 2. Radiated emission



## Conditions

Test : EMI  
 Model Name : MGFS3024□□/MGFW3024□□

○Photographs of Test Set-Up

### LINE CONDUCTION



### RADIATED EMISSION



○Testing circuitry

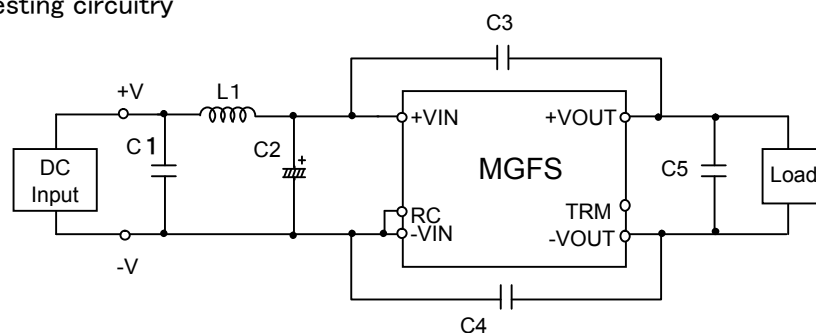


Fig.1 Testing circuitry 1

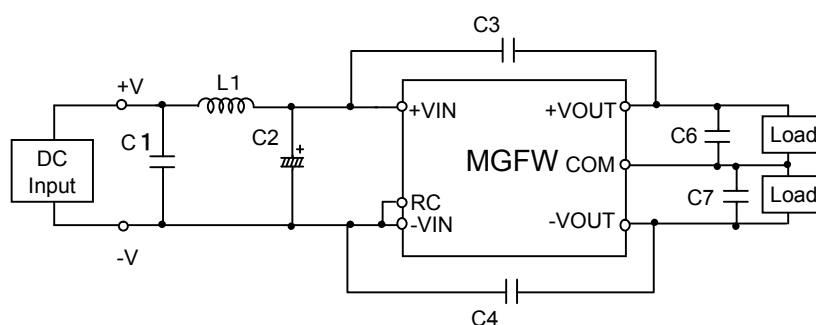


Fig.2 Testing circuitry 2

L1	: 0.6uH	CI8C-0R6	(KORIN ELECTRONICS)
C1	: 50V 4.7 $\mu$ F	Ceramic Capacitor	
C2	: 50V 100 $\mu$ F	Electrolytic Capacitor	
C3,C4	: 2kV 1000pF	Ceramic Capacitor	
C5,C6,C7	: 25V 22 $\mu$ F	Ceramic Capacitor	